

GC/MS

The Agilent 5975C series Gas Chromatograph/Mass Spectrometer (GC/MSD) provides flexibility, capabilities, and performance demanded by modern applications in all industries. The mass selective detector (MSD) can be configured for electron ionization or chemical ionization. Chemical ionization has been made as routine as electron ionization with automatic setup, including tuning and gas flow control. The system can run routine ammonia chemical ionization with an optional rough pump designed for corrosive chemicals.

The gas chromatograph and autosampler systems can be selected to meet laboratory requirements. For laboratories where space is limited, the MSD can be used with the compact Agilent 6850 GC. To save even more space, two GC/MS systems can be controlled by a single ChemStation. Other laboratories will want the full capabilities of the Agilent 6890 GC or the new high-performance 7890A GC configured with both the MSD and conventional GC detectors. Injection systems can range from an injector tower to a flexible CTC-PAL autosampling system. Other sampling devices are available from Agilent and third parties.

The 5975C Series GC/MSD gives you high performance and high productivity with features that will improve your analysis.

Trace Ion Detection technology will help in the detection of low-level compounds in complex matrices. In combination with the Deconvolution Reporting Software add-on, it is now possible to detect even lower level compounds that coelute-the type of analysis that was difficult without the help of Trace Ion Detection technology.

The programmable 350 °C source will increase the signal intensity for later eluting compounds. This improvement in signal is compound dependent.

The Gain Normalization Autotune will set the MSD in the best operating conditions, and these conditions will be consistent across instruments. The electronics of the 5975C systems allow a combination of both SIM and scan acquisitions, even for sub-one-second chromatographic peaks. To make this capability practical, the SIM ions and switching times can be automatically set up with the ChemStation software.

Retention time locking (RTL) maintains the retention times so that method maintenance is minimized when columns are clipped or the methods are transferred to other instruments. Method transfers are further simplified with the eMethod capabilities. Multi-site laboratories can easily transfer and run the same methods with the same retention times no matter what detector is used on the gas chromatograph. Optimized methods from the latest Agilent applications can be downloaded from the Web site and run in your laboratory.

The ChemStation software provides an extensive set of tools for all laboratories. In addition to basic quantitative capabilities, high volume laboratories in drug and environmental testing can generate reports specifically designed for their industry. The latest software even allows estimating concentrations of non-calibrated compounds based on calibrated compounds (SemiQuant). Laboratories doing qualitative analysis have access to extensive data manipulation tools developed based on customer requests. For complex samples, our



Deconvolution Reporting Software (DRS) combined with our unique DRS libraries provide quick screening capabilities for classes of compounds. For users who want to customize their operations, an extensive macro language is provided along with a flexible report writer.

Agilent GC/MSDs are known for their reliability, ruggedness, and long life. The Agilent 10-year use guarantee provides greater assurance for a low cost-of-ownership throughout its life.

The Agilent 5975C Series MSD system features:

- Proven ruggedness and reliability
- eMethods for simple method transfer
- SemiQuant for estimating concentrations of noncalibrated compounds
- Expanded qualitative analysis capabilities
- Inert electron ionization (EI) source for better performance on active compounds
- Higher sensitivity
- Mass range up to 1050 u
- High performance SIM/scan with automated SIM setup
- Mass stability—better than 0.10 u over 48 hours
- Performance electronics for 10,000 u/s scan speed (8,000 u/s write-to-disk)
- DRS and RTL ready
- Compatible with microfluidics flow controller and Quickswap
- Compatible with flip-top inlet sealing system for 6890 and 6850 and with turn-top for 7890A GC
- Proprietary hyperbolic gold-coated quadrupole
- Heatable quadrupole to 200 °C
- · Easy access to full ion optics
- High energy dynode and electron multiplier (EM) detector
- Two-MS control per PC
- Four simultaneous signal acquisitions (up to two MS)
- Intelligent sequencing for samples
- Compatibility with many third party sampling devices
- AutoCI for full automation of CI reagent gas and source tuning
- Choice of oil-free mechanical pumps (optional)
- Tested for ammonia CI
- Ten-year use guarantee

Agilent 5975C Series MSD System Data Sheet

Mass Spectrometer

| Mode (standard) | EI |
|----------------------------|--|
| Modes (optional) | PCI, NCI, EI with CI source |
| lon source type | Noncoated inert El source (optional for diffusion pump system) |
| Sources | El source provided with all systems; Cl source for PCI, NCI, and El added to Cl systems |
| lonization energy | 5–241.5 eV |
| Ionization current | 0–315 μA |
| Cl gases | Dual gas inlet |
| Transfer line temperature | 100–350 °C |
| lon source temperature | 150–350 °C |
| Quadrupole temperature | 106–200 °C |
| Filaments | Dual for El, single for Cl |
| Mass filter | Monolithic hyperbolic quadrupole |
| Mass filter protection | Entrance lens |
| Maximum mass | 1050 u |
| Mass resolution | Unit mass adjustable by tune |
| Mass axis stability | Better than 0.10 u/48 h |
| Detector | EM with replaceable horn |
| Dynamic range (electronic) | 10e6 |
| Scan rate (electronic) | Up to 10,000 u/s |
| Write-to-disk | Up to 8,000 u/s |
| SIM | 60 ions $	imes$ 100 groups |
| Pumping system | 65 L/s for the diffusion pump and 70 L/s or 262 L/s turbomolecular pump with 2.5 m ³ /hr mechanical pump |
| Total flow | 1.5 mL/min (diffusion) 2 mL/min (standard turbo) 4 mL/min (performance turbo) |
| Instrument control | Data system and local user interface |
| Maintenance access | Source, filaments, lenses, mass filter, and detector on removable plate |
| Maintenance scheduling | Early maintenance feedback |
| Gas Chromatograph | |
| Gas chromatograph | 6850, 6890, or 7890A GC |
| Autosampler | 6850, 7683, or CTC-PAL (all autosamplers are optional) |
| Liner replacement | Compatible with optional flip-top inlet sealing system for 6850 and 6890; turn-top system standard with 7890A GC |

| Injector | Split-splitless (standard), others available | Insta |
|--|--|--|
| Oven temperature | Ambient +4– 450 °C (6890 and 7890A GC) Ambient +5– 350 °C (6850) | All tes injecto colum |
| Oven ramps/plateaus | 6/7 for 6850 and 6890 20/21 for 7890A GC with negative ramps allowed | scanni peak ii tion pe |
| Carrier gases | Helium, hydrogen (and nitrogen, argon for GC detectors) | system |
| Electronic pneumatic control (EPC) | Auto pressure regulation for split/splitless, septum purge | El scan : |
| Carrier gas control modes | Constant pressure and flow modes; pressure and flow programmable | |
| Pressure range | 0–100 psi (standard), 0–150 psi (optional) with 0.01 psi resolution, pressure and temperature corrected for the 6850 and the 6890 and 0.001 psi resolution for the 7890A GC | PCI scar (methan NCI scar (methan |
| Retention-time locking | RTL ready | |
| Flow control | Compatible with optional capillary flow device controller | Othe El scan : |
| Data System | | (hydroge |
| eMethods | Transfer methods between the 6850, 6890, and 7890A Series MSDs | EI SIM s |
| Simultaneous MS and GC | Four signals (up to two MS) detector data acquisitions | PCI SIM |
| SIM/Scan | Automated SIM setup and synchronous SIM/scan operation | NCI SIM |
| lonization mode autotunes | EI, PCI, NCI | |
| Chemical ionization setup | Electronic mass flow control of reagent gases | PCI scar (ammon |
| High-mass confirmation | Verification test kit (optional) | |
| Application autotunes | One-click autotune for BFB, DFTPP | NCI sca |
| Quantitation setup | Automated | (ammon |
| Application reports | Environmental, drugs of abuse, aro- matics in gasoline | Troo |
| File import/export | Sequence file/quant and custom report | Result |
| Customization | Macro language, report writer | OFN u |
| Security | Password and audit trail | proces |
| Spectral libraries (optional) | NIST, Wiley, Pfleger-Mauer Drug, Stan pesticide | concer compa |
| Spectral and RTL databases (optional) | Pesticides and endocrine dis- rupters, hazardous chemcials, indoor air toxics, volatiles, PCBs, toxicology, FAMEs, flavors, organotin compounds | Trace R ⁻ Trace ar |
| 21CFR11 Compliance (optional) | 6890 software supported | • The |
| Other capabilities (optional) | Deconvolution linked with RTL database | flov • The |
| Support life | Ten-year use guarantee | fro |

Installation Checkout Specifications

All tests performed using an autosampler, split-splitless injector, and a 30 m \times 0.25 mm \times 0.25 μ m HP-5MS column. All scan determinations use continuous linear scanning across the entire mass range. Noise selection, peak integration, and RMS S/N (signal-to-noise) calculation performed by automated macro. Specifications are not comparable to those using different conditions. The system will exceed the following specifications at installation:

| El scan sensitivity | 1-μL injection of a 1-pg/μL OFN standard scanning from 50–300 u will give 200:1 and 100:1 S/N for turbo pump and diffusion pump systems, respectively, at nominal <i>m/z</i> 272 ion |
|-----------------------------------|--|
| PCI scan sensitivity (methane) | 1-µL injection of a 100-pg/µL BZP standard scanning from 80–230 u will give 125:1 S/N at nominal <i>m/z</i> 183 ion |
| NCI scan sensitivity (methane) | 2-μL injection of a 100-fg/μL OFN standard scanning from 50–300 u will give 600:1 S/N at nominal <i>m/z</i> 272 ion |

Other Sensitivity Specifications

| El scan sensitivity (hydrogen) | $1-\mu L$ injection of a $1-pg/\mu L$ OFN standard scanning from 50 to 300 u will give at nomi- nal m/z 272 ion 100:1 for turbo systems and 50:1 for the diffusion system |
|-----------------------------------|--|
| El SIM sensitivity | 1-μL injection of a 20-fg/μL OFN standard will give 10:1 S/N at nominal <i>m/z</i> 272 ion |
| PCI SIM sensitivity | 1-μL injection of a 1-pg/μL BZP standard will give 10:1 S/N at nominal <i>m/z</i> 183 ion |
| NCI SIM sensitivity | 1-μL injection of a 1-fg/μL OFN standard will give 10:1 S/N at nominal <i>m/z</i> 272 ion |
| PCI scan sensitivity (ammonia) | 1-μL injection of a 100-pg/μL BZP standard scanning from 80–230 u will give 500:1 S/N at nominal m/z 183 ion |
| NCI scan sensitivity (ammonia) | 2-μL injection of a 100-fg/μL OFN standard scanning from 50–300 u will give 300:1 S/N at nominal <i>m/z</i> 272 ion |

Trace Repeatability

Results are for three replicate splitless injections of 1-pg OFN using MS detection and automated integration and processing. Specifications using a different compound, concentration, detectors, or conditions, are not comparable.

| Trace RT repeatability | <0.0012 min | |
|------------------------|-------------|--|
| | | |

Trace area repeatability <2.0% RSD

Automation Features

- The system can automatically tune and adjust gas flows for chemical ionization operation.
- The system can automatically create a SIM method from a scan datafile of an injected standard.

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- The system can automatically screen for 926 entries in the pesticides and endocrine disruptors database based on spectra and RTs
- With the optional DRS, the system can produce a combined report showing library search results based on deconvoluted spectra along with quantitative results

Ease-of-Maintenance

- The GC inlet liner can be replaced in less than 1 minute without the use of tools when using the optional flip-top inlet sealing system for the 6850 and 6890N GCs. The 7890A GC comes standard with a turn-top inlet that will give you the same benefits.
- A glass window simplifies column positioning. It also shows ion source type, filament operation, and electrical connections.
- The source, filaments, lenses, quadrupole, and EM can be removed from the instrument as one unit in less than 1 minute after venting.
- The optional micro ion gauge controller can be replaced without removal of the mass spectrometer covers.

Safety, Regulatory Compliance, and Operational Conditions

The instrument is designed and manufactured under a quality system registered to ISO 9001. The instrument complies with international regulatory, safety, and electromagnetic compatibility requirements. In addition, further testing was done under Agilent standards to assure operation after delivery and long-term usage.

See the 5975 page at

http://www.chem.agilent.com/Scripts/PDS.asp?lPage=34426 for further information and typical product testing videos.

| Safety | Canadian Standards Association (CSA): CAN/CSA-C22.2 No. 61010- 1-04 |
|-------------------------------|---|
| | CSA/Nationally Recognized Test Laboratory (NRTL): UL 61010-1 |
| | International Electrotechnical Commission (IEC): 61010-1 |
| | EuroNorm (EN): 61010-1 |
| Electromagnetic compatibility | CISPR11/EN55011: Group 1, Class A |
| | |

| Sound emission | EN 27779:1991 - sound pressure Lp <70 db |
|-----------------------|---|
| Power | 110–130 VAC ±5%, 60 Hz only 200–210 VAC ±5%, 50/60 Hz 220–240 VAC ±5%, 50/60 Hz |
| Operating environment | 15–35 °C, 40–80% relative humidity – noncondensing (operational) |
| | -20–70 °C, 0–95% relative humidity – noncondensing (storage) |

Physical Requirements (with the Agilent 6890 or 7890A GC)

| Dimensions (GC/MS) | $88\ cm\ (w)\times 56\ cm\ (d)\times 50\ cm\ (h)$ Additional space should be added for the data system and printer. |
|--------------------|---|
| Weight (GC/MS) | 81 to 96 kg (depending on configuration) |

For More Information

For more information on our products and services, visit our Web site at www.agilent.com/chem.

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